Amendments To The Claims

1. (original) A method for refining a length of a scan line, wherein said scan line is produced from a facet of a scanning device, comprising the steps of:

(a) acquiring a plurality of scan line lengths produced from a facet;

(b) determining from said plurality of scan line lengths, an average scan line length for said facet; and

(c) determining from said average scan line length, a scan line length correction for said facet.

2. (original) The method of claim 1, wherein said facet is one of a plurality of facets on a rotating reflector, and wherein said method further comprises the step of obtaining a number from a cyclic counter to identify said facet and to associate said plurality of scan line lengths with said facet when determining said average scan line length.

3. (original) The method of claim 1, wherein said scanning device produces pixels at a dot imaging frequency, and wherein said plurality of scan line lengths is acquired from a counter that is clocked at a rate of less than 8 times said dot imaging frequency.

4. (original) A system for refining a length of a scan line, wherein said scan line is produced from a facet of a scanning device, comprising:

(a) means for acquiring a plurality of scan line lengths produced from a facet;

(b) means for determining from said plurality of scan line lengths, an average scan line length for said facet; and

(c) means for determining from said average scan line length, a scan line length correction for said facet.

5. (original) The system of claim 4, wherein said facet is one of a plurality of facets on a rotating reflector, and wherein said system further comprises a cyclic counter for providing a number for said facet to identify said facet and to associate said plurality of scan line lengths with said facet when determining said average

scan line length.

6. (original) The system of claim 4, wherein said scanning device produces pixels at a dot imaging frequency, and wherein said acquiring means comprises a counter that is clocked at a rate of less than 8 times said dot imaging frequency.

7. (original) A storage medium that includes instructions for controlling a processor to execute a method for refining a length of a scan line, wherein said scan line is produced from a facet of a scanning device, said storage medium comprising:

(a) first instructions for controlling said processor to acquire a plurality of scan line lengths produced from a facet;

(b) second instructions for controlling said processor to determine from said plurality of scan line lengths, an average scan line length for said facet; and

(c) third instructions for controlling said processor to determine from said average scan line length, a scan line length correction for said facet.

8. (original) The storage medium of claim 7, wherein said facet is one of a plurality of facets on a rotating reflector, and wherein said storage medium comprises further instructions for controlling said processor to obtain a number from a cyclic counter to identify said facet and to associate said plurality of scan line lengths with said facet when determining said average scan line length.

9. (original) The storage medium of claim 7, wherein said scanning device produces pixels at a dot imaging frequency, and wherein said scan line length is acquired from a counter that is clocked at a rate of less than 8 times said dot imaging frequency.

10-30. (cancelled)